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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s):	Ying EE Yip et al.	Examiner:	Holder, Regina Neal
Serial No.:	09/851,767	Group Art Unit:	2651
Filed:	May 9, 2001	Docket No.:	STL9663
Title:	Pattern-Based Defect Description Method		

Mail Stop Non-Fee Amendment
Commissioner For Patents
PO Box 1450
Alexandria, VA 22313-1450

AMENDEMNT

Madam:

In response to the Office Action mailed May 7, 2003, please amend the present application as follows and consider the following remarks.

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Technology Center 2600